Special Issue

Optical Imaging and Sensing: From Design to Its Practical Use

Message from the Guest Editor

Various sensors and new imaging technologies are driving information technology advancements. This poses new challenges to the advancement of optical sensing and imaging and software solutions. Therefore, this Special Issue intends to present new ideas and experimental results in the field of high-performance optical sensing and imaging, from design to practical use. Research on high-performance optical sensing and imaging includes, but is not limited to, ultra-violet, visible and infrared sensing and imaging, machine vision, automatic target detection, image processing and analysis, 3D imaging, artificial intelligence and computational imaging, frontier issues in optical imaging and sensing, and other related technologies.

Guest Editor

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As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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